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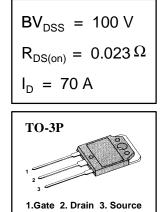
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Advanced Power MOSFET

FEATURES

- Avalanche Rugged Technology
- Rugged Gate Oxide Technology
- Lower Input Capacitance
- Improved Gate Charge
- Extended Safe Operating Area
- 175°C Operating Temperature
- Lower Leakage Current : 10 µA (Max.) @ V_{DS} = 100V
- Lower $R_{DS(ON)}$: 0.018 Ω (Typ.)





Absolute Maximum Ratings

Symbol	Characteristic	Value	Units		
V _{DSS}	Drain-to-Source Voltage	100	V		
	Continuous Drain Current (T _C =25 °C)		70	^	
۱ _D	Continuous Drain Current (T _c =100 °	49.2	A		
I _{DM}	Drain Current-Pulsed	0	280	Α	
V _{GS}	Gate-to-Source Voltage	± 20	V		
E _{AS}	E _{AS} Single Pulsed Avalanche Energy (2)		1633	mJ	
I _{AR}	Avalanche Current	0	70	Α	
E _{AR}	Repetitive Avalanche Energy	0	30	mJ	
dv/dt	Peak Diode Recovery dv/dt	3	6.5	V/ns	
	Total Power Dissipation (T _c =25 ° _C)		300	W	
P _D	Linear Derating Factor		2.0	W/°C	
	Operating Junction and				
Τ _J , Τ _{STG}	Storage Temperature Range	- 55 to +175	°C		
	Maximum Lead Temp. for Soldering	200			
TL	Purposes, 1/8" from case for 5-seco	onds	300		

Thermal Resistance

Symbol	Characteristic	Тур.	Max.	Units
R _{θJC}	Junction-to-Case		0.5	
R _{ecs}	R _{6CS} Case-to-Sink			°C /W
R _{θJA}	Junction-to-Ambient		40	



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Rev. B

Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition	
BV _{DSS}	Drain-Source Breakdown Voltage	100			V	V _{GS} =0V,I _D =250	
$\Delta \text{BV} / \Delta \text{T}_{\text{J}}$	Breakdown Voltage Temp. Coeff.		0.12		V/°C	I _D =250μA See Fig 7	
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	V _{DS} =5V,I _D =250μA	
	Gate-Source Leakage, Forward			100 nA		V _{GS} =20V	
I _{GSS}	Gate-Source Leakage, Reverse			-100		V _{GS} =-20V	
	Desir to Course Lookana Current			10	μA	V _{DS} =100V	
I _{DSS}	Drain-to-Source Leakage Current			100		V _{DS} =80V,T _C =150°C	
Б	Static Drain-Source			0.023	0	V _{cs} =10V.I _b =35A ④	
$R_{DS(on)}$	On-State Resistance				Ω	V _{GS} =10V,I _D =35A ④	
9 _{fs}	Forward Transconductance		53.51		Ω	V _{DS} =40V,I _D =35A (4)	
C _{iss}	Input Capacitance		3750	4870			
C _{oss}	Output Capacitance		850	980	pF	V _{GS} =0V,V _{DS} =25V,f =1MHz See Fig 5	
C _{rss}	Reverse Transfer Capacitance		375	430		See rig 5	
t _{d(on)}	Turn-On Delay Time		22	60		V _{DD} =50V,I _D =70A,	
t _r	Rise Time		24	60		$R_{G} = 5.3\Omega$	
t _{d(off)}	Turn-Off Delay Time		112	240	ns	Ű	
t _f	Fall Time		84	180		See Fig 13 ④⑤	
Q_{g}	Total Gate Charge		151	195		V _{DS} =80V,V _{GS} =10V,	
Q_{gs}	Gate-Source Charge		31		nC	I _D =70A	
Q_{gd}	Gate-Drain("miller") Charge		66			See Fig 6 & Fig 12 46	

Electrical Characteristics (T_C=25°C unless otherwise specified)

Source-Drain Diode Ratings and Characteristics

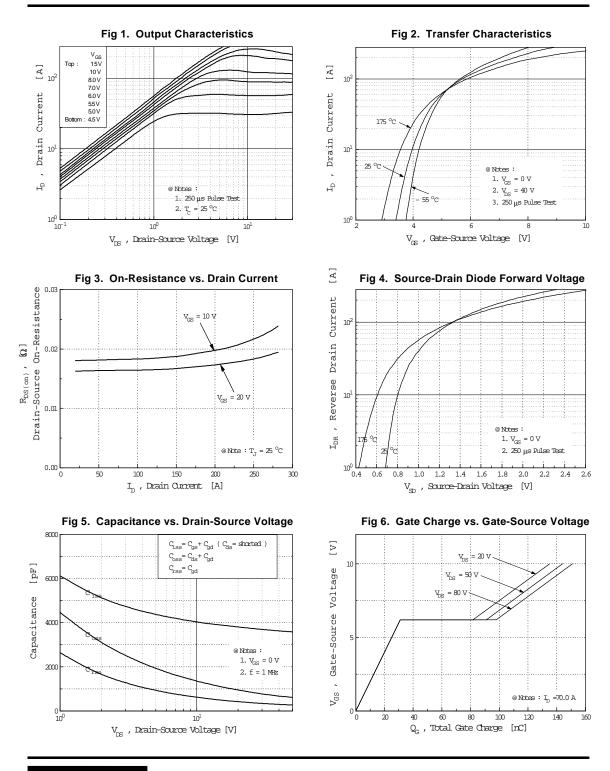
Symbol	Characteristic		Min.	Тур.	Max.	Units	Test Condition
ا _s	Continuous Source Current				70	А	Integral reverse pn-diode
I _{SM}	Pulsed-Source Current (D			280	A	in the MOSFET
V _{SD}	Diode Forward Voltage	Ð			1.6	V	T _J =25°C,I _S =70A,V _{GS} =0V
t _{rr}	Reverse Recovery Time			143		ns	T _J =25°C,I _F =70A
Q _{rr}	Reverse Recovery Charge			0.72		μC	$di_F/dt=100A/\mu s$

Notes;

- ① Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature
- 2 L=0.5mH, I_{AS} =70A, V_{DD} =25V, R_{G} =27 Ω , Starting T_{J} =25°C
- $\begin{array}{ll} \hline \textbf{3} & I_{SD} \leq 70\text{A}, \text{ di/dt} \leq 530\text{A}/\mu\text{s}, \text{ V}_{DD} \leq \text{BV}_{DSS} \text{ , Starting } \text{T}_{\text{J}} = 25^{\circ}\text{C} \\ \hline \textbf{4} & \text{Pulse Test : Pulse Width} = 250 \ \mu\text{s}, \text{ Duty Cycle} \quad \leq 2\% \end{array}$
- **(5)** Essentially Independent of Operating Temperature



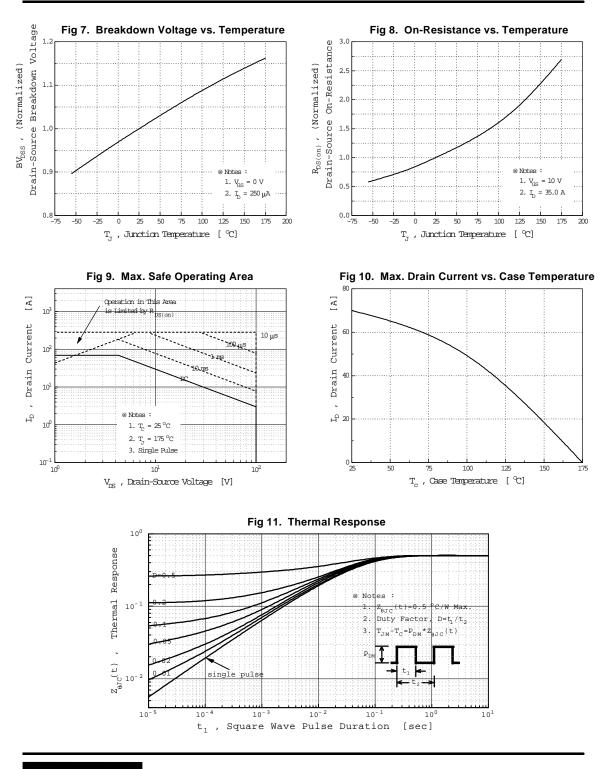




FAIRCHILD

SSH70N10A

N-CHANNEL POWER MOSFET



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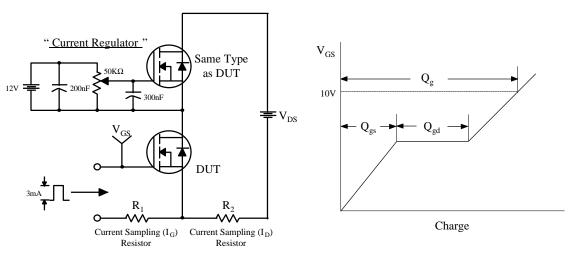


Fig 12. Gate Charge Test Circuit & Waveform



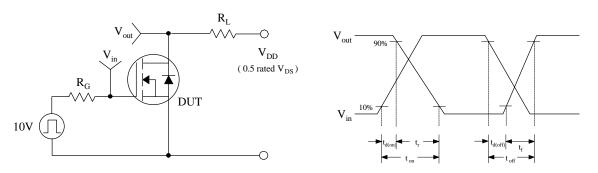
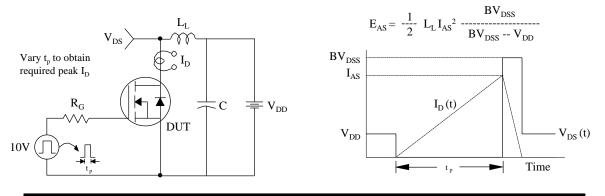


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms





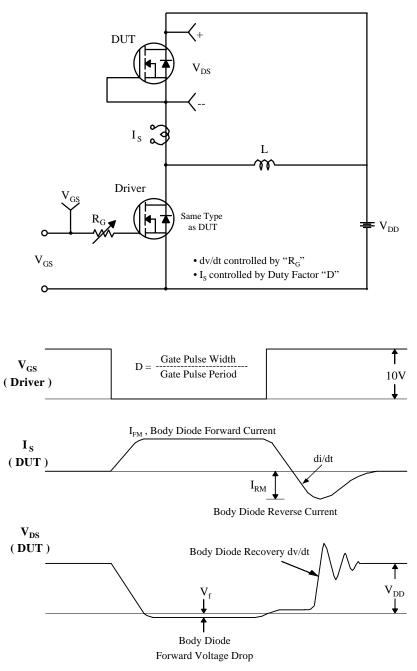


Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



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